Supporting Information for:
Substrate-Independent Light Confinement in Bioinspired All-Dielectric Surface Resonators

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**Figure S1: Numerical Simulation of T-bar Structure.** FDTD simulation of the reflectance of an acrylic $\epsilon = 2.235$ T-bar structure (see inset of (b)) with periodicity $a$, height $h = 0.88a$, thickness $t = 0.22a$ on substrate with dielectric constants (a) $\epsilon_{\text{substrate}} = \epsilon_{\text{air}} = 1$, (b) $\epsilon_{\text{substrate}} = \epsilon_{\text{t-bar}} = 2.235$, (c) $\epsilon_{\text{substrate}} = 6 > \epsilon_{\text{t-bar}}$. The incident light is polarized in the y-direction. Inset in each figure: FDTD mode profiles ($E_y$) and Q-factors of the resonance modes at wavelengths equal to the first-order Fano resonance peaks indicated.
Figure S2: Numerical Simulation of Suspended Grating. RCWA simulation of the reflectance of an acrylic $\epsilon = 2.235$ grating (see inset of (b)) with periodicity $a$, width $w = 0.22a$, thickness $t = 0.22a$ suspended at $h = 0.56a$ above a substrate with dielectric constants (a) $\epsilon_{\text{substrate}} = \epsilon_{\text{air}} = 1$, (b) $\epsilon_{\text{substrate}} = \epsilon_{\text{slab}} = 2.235$, (c) $\epsilon_{\text{substrate}} = 6 > \epsilon_{\text{slab}}$. The incident light is polarized in the $y$-direction. Inset in each figure: FDTD mode profiles ($E_y$) and Q-factors of the resonance modes at wavelengths equal to the first order Fano-resonance peaks indicated.
Figure S3: Microspectrometer Setup for Reflectance Measurement. Schematic of CRAIC QDI 2010 microspectrometer used to excite zigzag sample at normal incidence and collect reflected light at normal ±2°.